	Application No.	Applicant(s)
N	10/659,898	KUZMA, ANDREW J.
Notice of Allowability	Examiner	Art Unit
	Jennifer M. Dolan	2813
The MAILING DATE of this communication appear All claims being allowable, PROSECUTION ON THE MERITS IS (herewith (or previously mailed), a Notice of Allowance (PTOL-85) of NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RICO of the Office or upon petition by the applicant. See 37 CFR 1.313	OR REMAINS) CLOSED in this apport of the appropriate communication GHTS. This application is subject to	olication. If not included will be mailed in due course. THIS
1. \boxtimes This communication is responsive to <u>AF Amdt 4/7/06 + Inter</u>	<u>rview of 5/3/06</u> .	
2. The allowed claim(s) is/are <u>1-3,5-8 and 27-29</u> .		
 3. Acknowledgment is made of a claim for foreign priority und a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 	been received.	
2. Certified copies of the priority documents have	·· —	
3. Copies of the certified copies of the priority doc	uments have been received in this	national stage application from the
International Bureau (PCT Rule 17.2(a)).		
* Certified copies not received:		
Applicant has THREE MONTHS FROM THE "MAILING DATE" on noted below. Failure to timely comply will result in ABANDONMETHIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		complying with the requirements
4. A SUBSTITUTE OATH OR DECLARATION must be submit INFORMAL PATENT APPLICATION (PTO-152) which gives		
5. CORRECTED DRAWINGS (as "replacement sheets") must	be submitted.	
(a) \square including changes required by the Notice of Draftsperso	on's Patent Drawing Review (PTO-	948) attached
1) hereto or 2) to Paper No./Mail Date		
(b) ☐ including changes required by the attached Examiner's Paper No./Mail Date	Amendment / Comment or in the C	Office action of
Identifying indicia such as the application number (see 37 CFR 1.8 each sheet. Replacement sheet(s) should be labeled as such in the		
 DEPOSIT OF and/or INFORMATION about the depos attached Examiner's comment regarding REQUIREMENT F 		
Attachment(s) 1. ☐ Notice of References Cited (PTO-892)	5. Motion of Informal P	atont Application (PTO 152)
2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)	6. ☐ Interview Summary	atent Application (PTO-152)
	Paper No./Mail Dat	e
 Information Disclosure Statements (PTO-1449 or PTO/SB/08 Paper No./Mail Date 	B), 7. ⊠ Examiner's Amendn	nent/Comment
Examiner's Comment Regarding Requirement for Deposit of Biological Material	8. X Examiner's Stateme	ent of Reasons for Allowance
	9. 🗆 Other	Mitchesof
		ARL WHITEHEAD, JR VISORY PATENT EXAMINEF: HNOLOGY CENTER 2800

DETAILED ACTION

Examiner's Amendment

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Todd Becker on 3 May 2006.

The application has been amended as follows:

The After Final Amendment filed on 4/7/06 has been entered.

In line 6 of claim 1 (from the 4/7/06 Amendment), --formed on the wafer and-has been inserted between "test structure" and "comprising"

Claims 19-22 have been canceled.

Allowable Subject Matter

- 2. Claims 1-3, 5-8, and 27-29 are allowed.
- 3. The following is an examiner's statement of reasons for allowance:

The primary reason for allowance is the combination of a test structure formed on the wafer, the test structure being coupled to the front or back facet of a device to redirect the light

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beam emitted from the front or back facet, and the test structure being removable, in addition to the other limitations in the claims.

Each reference of the prior art of record is deficient in at least one of the recited limitations above, with no viable or reasonable way to modify the reference in order to meet the claimed limitations.

The closest prior art of record is US 6,668,000 to Choa, which teaches a test structure incorporated on a light emitting device wafer, where the test structure is considered removable (i.e., capable of being removed). In Choa, however, the test structure is disposed internal to the device, such that a small fraction of the light is diverted for testing, and such that the beams emitted from the front and back facets are not redirected. While it is considered possible to remove the test structure in Choa, its position internal to the laser cavity does not generally facilitate easy removal of the test structure, and it is clear that removal of the test structure in Choa is not intended. Furthermore, the light redirected by the test structure in Choa comprises only a small fraction of the light that is emitted through the facet. The claimed invention, however, differs critically from Choa in that a test structure positioned external to the laser cavity and coupled to one of the facets enables easy removal through cleaving, and additionally, redirects a much greater portion of the emitted light for testing.

Other prior art references teach forming a redirecting structure having a substantially similar configuration as the test structure coupled to the front facet of a laser diode, with both the laser and the redirecting structure provided on the same substrate (see US 6,459,716 to Lo et al.). In this case, the redirecting structure is used to convert an edge-emitting device into a surface-emitting device, and hence, cannot in any reasonable way be construed as being a "removable"

structure, since the removal of the redirecting structure would destroy the intended function of the device.

Yet another set of similar prior art references teach discrete light-emitting devices having a front facet coupled to a re-directing structure provided on a separate submount (see US 6,487,224 to Ohashi et al. or US 6,449,296 to Hamasaki et al.). Hence, these references fail to teach forming the light emitting structure and the test structure on the same wafer. Since the provision of a test/redirecting structure on the wafer allows for testing and analysis of the light emitting device before singulation from the wafer, and since the methods required for integrating a redirecting test structure with the light emitting device on the same wafer are not trivial, it is the Examiner's opinion that it would not be reasonable to incorporate features located on the submount or package substrate directly into the device wafer.

Since all of the differences between the prior art of record and the claimed invention produce critical and significant effects, since there is no reasonable motivation to modify the prior art in order to obtain the claimed invention, it is the Examiner's opinion that the invention as claimed would not have been obvious to a person having ordinary skill in the art.

4. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

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Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jennifer M. Dolan whose telephone number is (571) 272-1690. The examiner can normally be reached on Monday-Friday 8:30am-5:00pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Carl W. Whitehead, Jr. can be reached on (571) 272-1702. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Jennifer M. Dolan Examiner Art Unit 2813

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